

Figure 4. Op-amp used in the bandgap reference.

Table 1. Circuit components

Components	Value/Size M(W/L)
M2, M3	16(6um/6um)
R2,R3	103k ohms
R1	10k ohms
MP10, MP11	2(20um/2um)
MP12	8(2um/2um)
MP13	32(2um/2um)
MN10,MN11	4(2um/2um)
MN12	40(2um/2um)
R _z , C _c	1k ohms , 2pF
MN41, MN42	2um/2um

3. SIMULATION RESULTS

3.1. Nominal performance

Simulation has been carried out using a 0.8um BiCMOS technology. The temperature dependency for both the conventional and proposed bandgap reference is shown in Fig.5. Both waveforms exhibit comparable temperature coefficients over the range from -40°C to 125°C . For simplicity, the aspect ratios for MN41 and MN42 are the same. This gives a unity DC gain for that branch which still maintains the same loop-gain as in the conventional circuit. The current consumption of the branch is only $2\mu\text{A}$. The PSR performances at room temperature between the two circuits are compared in Fig.6. The proposed circuit is shown to have improved the PSR at low frequency by approximately 30dB. Using equation (3) and (4), the PSRs are calculated as 77.1dB and 107.4dB respectively while the simulated values are 77.4dB and 110.3dB. The simulation results are closed to that of the theoretical evaluated values. The simulation results are summarized in Table 2.

Table 2. Nominal simulation results

	Conventional	Improved
Mean I_{DD}	33uA	35uA
Mean V_{BG}	1.208	1.207
Temperature Drift	3.1mV in -40°C to 125°C	2.8mV in -40°C to 125°C
PSR at DC	77.4dB	110.3dB
PSR at 1kHz	47.3dB	98.4dB

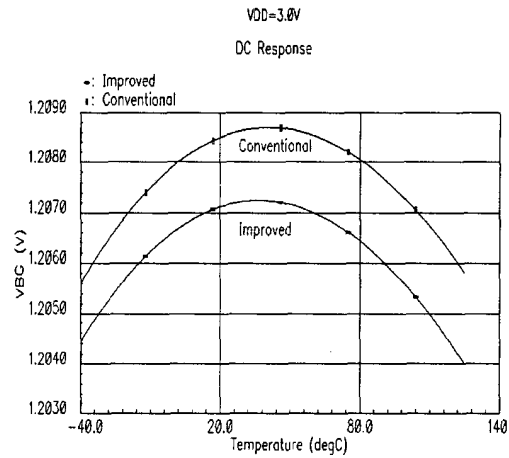


Figure 5. Temperature dependence of reference voltage.

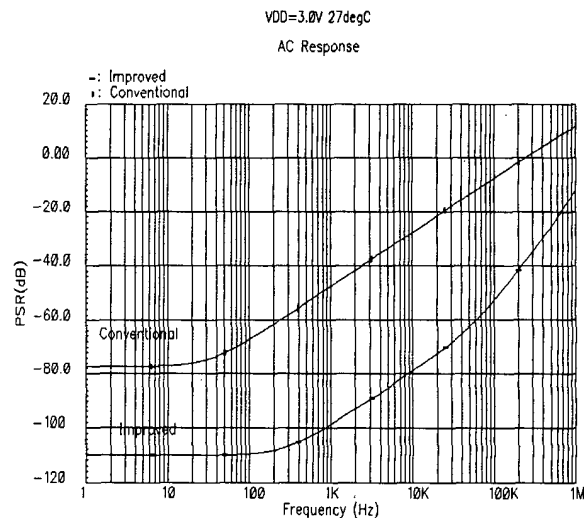


Figure 6. PSR of bandgap reference between conventional and improved reference circuits.

3.2. Temperature and process variation

To verify the robustness of the improved bandgap reference, the circuit has been simulated under different temperature and process conditions. The performance is summarized in Table 3. It is shown that over a wide temperature range, the improved bandgap reference has a higher PSR at low and medium frequency. Simulation has also been carried using two extreme process models i.e., “weak” and “strong” models which correspond to a deviation of about 20% of Idrive characteristics (drain current measured when transistor biased in triode region) from the nominal model. The results are compared in Figure 7. It is shown the improved bandgap reference yields a reasonably good PSR performance across the process variations.

Table 3. Simulation results of bandgap reference with temperature variation.

	Conventional	Improved
	DC, 1kHz	DC, 1kHz
-40 degC	77.2dB, 48.4dB	108.6dB, 103.8dB
25degC	77.4dB, 47.5dB	110.0dB, 98.5dB
125degC	78.0dB, 46.5dB	101.0dB, 93.1dB

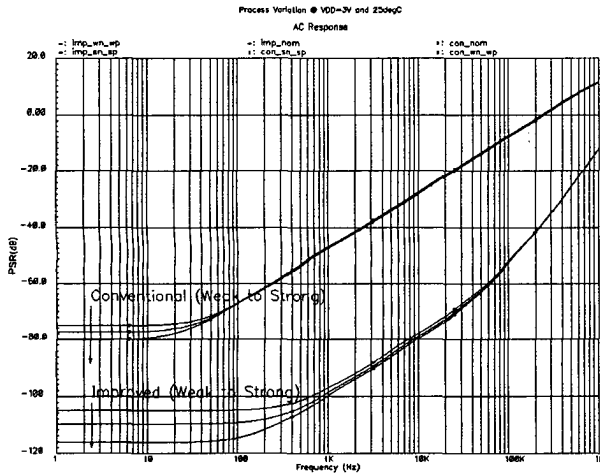


Figure 7. PSR of bandgap reference between conventional and improved reference circuits over process corners.

4. CONCLUSION

By incorporating a simple voltage subtractor circuit, the PSR of a conventional bandgap reference could achieve significant improvement. The proposed circuit does not add much complexity to the original bandgap reference. It

also consumes little silicon space and power, and is suitable for low voltage operation. The theoretical calculation of PSR matches closely with the simulated value. The improved bandgap reference is shown to have good PSR performance across temperature and process variation as compared to the conventional implementation.

5. REFERENCES

- [1] K-M Tham and K. Nagaraj, “A Low Supply Voltage High PSRR Voltage Reference in CMOS process,” *IEEE J. Solid State Circuits*, vol.30, pp.31-35, 1995.
- [2] T.L. Brooks and A.L. Westwick, “A Low-Power Differential CMOS Bandgap Reference”, in *ISSCC Dig. Tech. Papers*, pp248-249, 1994.
- [3] B. Razavi, *Design of Analog CMOS Integrated Circuits*, McGraw-Hill, 2001.
- [4] M.S.J. Steyart and W.M.C. Sansen, “Power supply rejection ratio in operational transconductance amplifiers”, *IEEE Trans. Circuits and Systems*, vol. 37, pp.1077-1084, 1990.
- [5] G. Giustolisi and G.Palumbo, “Detailed Frequency Analysis of Power Supply Rejection in Brokaw Bandgap,” *Proc. IEEE Intl. Symp. Circ. and Syst.*, pp.1731-1734, 2001.
- [6] M. G. Johnson, “An input-free V_{TP} and V_{TN} extractor circuits realized on the same chip,” *Analog Integrated Circuits and Signal Processing*, pp.151-157, 1999.